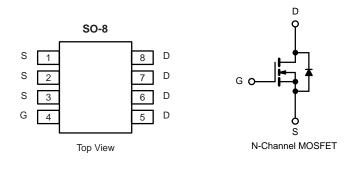


N-Channel 150 V (D-S) MOSFET

PRODUCT SUMMARY						
V _{DS} (V)	R _{DS(on)} (Ω)	I _D (A) ^a	Q _g (Typ.)			
150	0.080 at V _{GS} = 10 V	5.4	23 nC			
150	0.085 at V _{GS} = 8 V	4.5	23110			



FEATURES

- Halogen-free According to IEC 61249-2-21
 Definition
- Extremely Low Q_{gd} for Switching Losses
- 100 % R_g Tested
- 100 % Avalanche Tested
- Compliant to RoHS Directive 2002/95/EC

APPLICATIONS

• Primary Side Switch



Available

Parameter	Symbol	Limit	Unit	
Drain-Source Voltage		V _{DS}	150	V
Gate-Source Voltage		V _{GS}	± 20	
	T _C = 25 °C		5.4	
Continuous Drain Current (T 150 °C)	T _C = 70 °C		5.1	
Continuous Drain Current ($T_J = 150 \ ^\circ C$)	T _A = 25 °C	I _D	5.0 ^{b, c}	
	T _A = 70 °C		4.5 ^{b, c}	Α
Pulsed Drain Current		I _{DM}	22	A
Continuous Source-Drain Diode Current	T _C = 25 °C		4.5	
Continuous Source-Drain Diode Current	T _A = 25 °C	I _S	2.6 ^{b, c}	
Single Pulse Avalanche Current	L = 0.1 mH	I _{AS}	20	
Single Pulse Avalanche Energy		E _{AS}	20	mJ
	T _C = 25 °C		5.9	
Maximum Power Dissipation	T _C = 70 °C	P _D	3.8	W
	T _A = 25 °C		3.1 ^{b, c}	VV
	T _A = 70 °C	1	2 ^{b, c}	
Operating Junction and Storage Temperature	T _J , T _{stq}	- 55 to 150	°C	

THERMAL RESISTANCE RATINGS							
	Symbol	Typical	Maximum	Unit			
t ≤ 10 s	R _{thJA}	33	40	°C/W			
Steady State	R _{thJF}	17	21	0/10			
	t ≤ 10 s	$\begin{array}{c c} & \textbf{Symbol} \\ \hline t \leq 10 \text{ s} & \textbf{R}_{thJA} \end{array}$	Symbol Typical t ≤ 10 s R _{thJA} 33	Symbol Typical Maximum t ≤ 10 s R _{thJA} 33 40			

Notes:

a. Based on T_C = 25 °C.

b. Surface mounted on 1" x 1" FR4 board.

c. t = 10 s.

d. Maximum under steady state conditions is 80 °C/W.

SPECIFICATIONS ($T_J = 25 \degree C$) Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static	Symbol		IVIII.	тур.	Wax.	Onic
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} = 0 V, I _D = 250 μA	150			V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	VGS = 0 V, 1D = 200 µA	100	172		mV/°C
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I _D = 250 μA		- 10		
		$V_{DS} = V_{GS}$, $I_D = 250 \ \mu A$	1.2	10	2.5	V
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}$, $I_D = 250 \mu A$ $V_{DS} = 0 V, V_{GS} = \pm 20 V$	1.2			nA
Gate-Source Leakage	I _{GSS}				± 100	nA
Zero Gate Voltage Drain Current	I _{DSS}	$V_{DS} = 100 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$				μA
On Otata Dania Quananta		$V_{DS} = 100 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 55 \text{ °C}$	20		10	
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 10 \text{ V}, V_{GS} = 10 \text{ V}$	30	0.000	0.000	A
Drain-Source On-State Resistance ^a	R _{DS(on)}	$V_{GS} = 10 V, I_D = 5 A$		0.080	0.090	Ω
		$V_{GS} = 8 \text{ V}, \text{ I}_{D} = 5 \text{ A}$			0.095	
Forward Transconductance ^a	9 _{fs}	V _{DS} = 15 V, I _D = 5 A		23		S
Dynamic ^b			T	T .=	T	
Input Capacitance	C _{iss}			1735		pF
Output Capacitance	C _{oss}	$V_{DS} = 50 \text{ V}, V_{GS} = 0 \text{ V}, \text{ f} = 1 \text{ MHz}$		160		
Reverse Transfer Capacitance	C _{rss}			37		
Total Gate Charge	Q _q	$V_{DS} = 75$ V, $V_{GS} = 10$ V, $I_{D} = 5$ A		28.5	43	- nC
	Ű			23	35	
Gate-Source Charge	Q _{gs}	V_{DS} = 75 V, V_{GS} = 8 V, I_D = 5 A		8		
Gate-Drain Charge	Q _{gd}			6.5		
Gate Resistance	R _g	f = 1 MHz		0.85	1.3	Ω
Turn-on Delay Time	t _{d(on)}			14	21	-
Rise Time	t _r	V_{DD} = 50 V, R_L = 10 Ω		12	18	
Turn-Off Delay Time	t _{d(off)}	${\sf I}_{\sf D}\cong$ 5 A, ${\sf V}_{\sf GEN}$ = 10 V, ${\sf R}_{\sf g}$ = 1 Ω		22	33	
Fall Time	t _f			6	10	ns
Turn-On Delay Time	t _{d(on)}			16	24	115
Rise Time	t _r	V_{DD} = 50 V, R_{L} = 10 Ω		12	18	-
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 5 \text{ A}, V_{\text{GEN}} = 8 \text{ V}, R_g = 1 \Omega$		20	30	
Fall Time	t _f			7	12	
Drain-Source Body Diode Characteristi	cs					
Continuous Source-Drain Diode Current	۱ _S	T _C = 25 °C			7.7	•
Pulse Diode Forward Current ^a	I _{SM}	-			50	A
Body Diode Voltage	V _{SD}	I _S = 2.6 A		0.77	1.2	V
Body Diode Reverse Recovery Time	t _{rr}	~	1	63	95	ns
Body Diode Reverse Recovery Charge	Q _{rr}			110	165	nC
Reverse Recovery Fall Time	t _a	$I_F = 5 \text{ A}, \text{ dI/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 ^\circ\text{C}$		49		
Reverse Recovery Rise Time	t _b			14		ns

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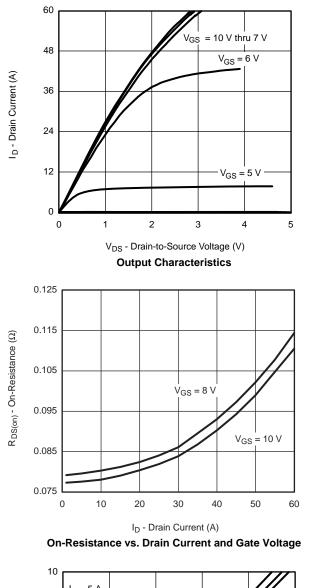
Notes:

a. Pulse test; pulse width $\leq 300~\mu\text{s},$ duty cycle $\leq 2~\%$

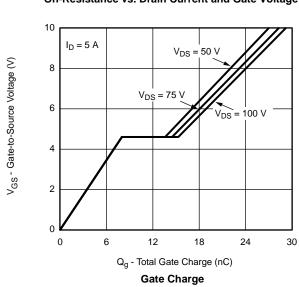
a. Guaranteed by design, not subject to production testing.

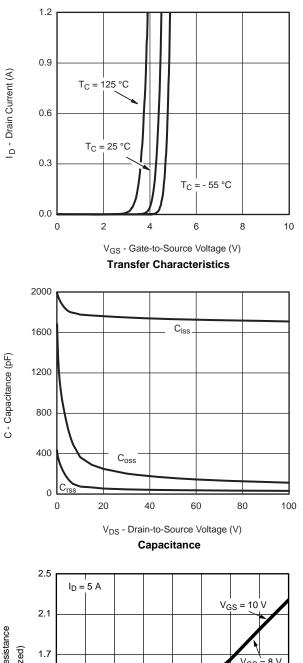
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

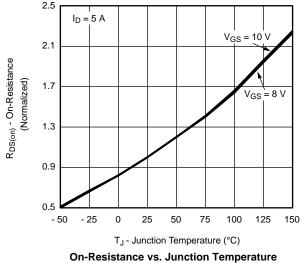




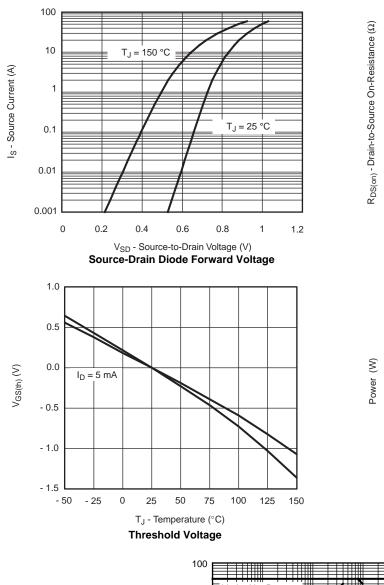
TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



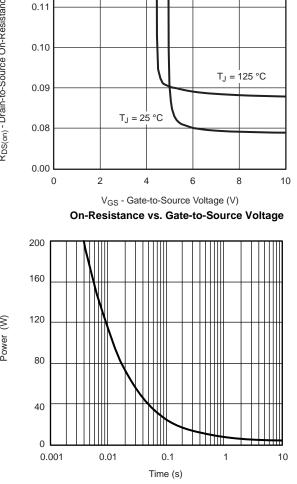






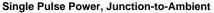


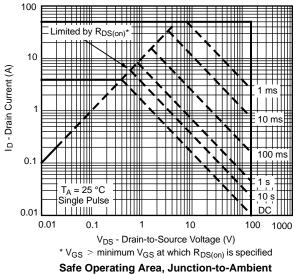
TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



0.12

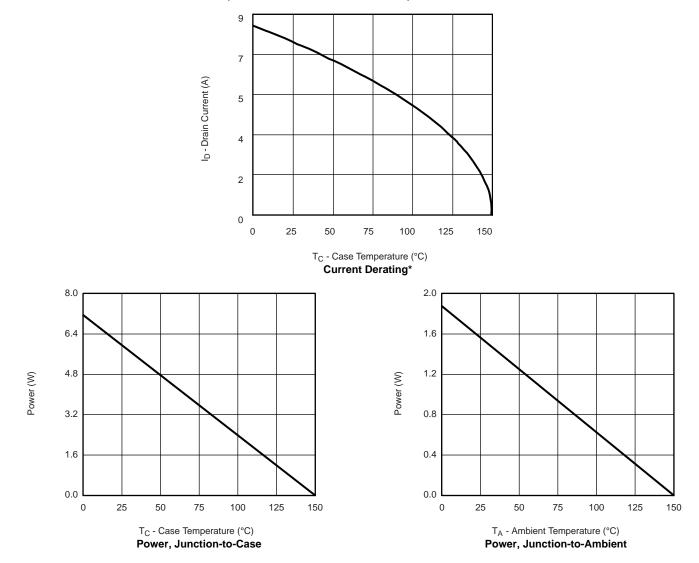
I_D = 5 Å







TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

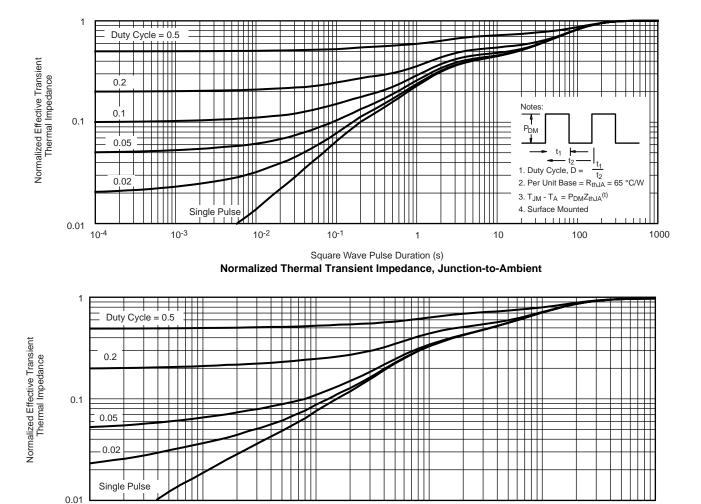


* The power dissipation P_D is based on $T_{J(max)}$ = 150 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.

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TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

10⁻³



Square Wave Pulse Duration (s)

10⁻²

Normalized Thermal Transient Impedance, Junction-to-Foot

10-1

1

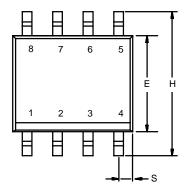
10

10⁻⁴



SOIC (NARROW): 8-LEAD

JEDEC Part Number: MS-012



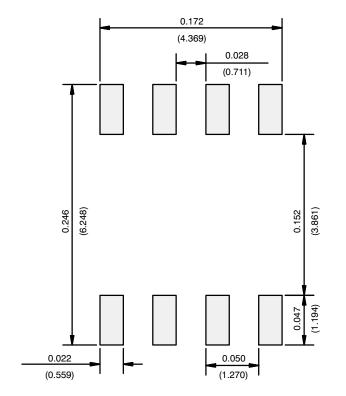


	MILLIM	IETERS	INCHES		
DIM	Min	Мах	Min	Max	
A	1.35	1.75	0.053	0.069	
A ₁	0.10	0.20	0.004	0.008	
В	0.35	0.51	0.014	0.020	
С	0.19	0.25	0.0075	0.010	
D	4.80	5.00	0.189	0.196	
E	3.80	4.00	0.150	0.157	
е	1.27 BSC		0.050 BSC		
н	5.80	6.20	0.228	0.244	
h	0.25	0.50	0.010	0.020	
L	0.50	0.93	0.020	0.037	
q	0°	8°	0°	8°	
S	0.44	0.64	0.018	0.026	
ECN: C-06527-Rev. I, 11-Sep-06 DWG: 5498					

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RECOMMENDED MINIMUM PADS FOR SO-8



Recommended Minimum Pads Dimensions in Inches/(mm)



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